

N-Channel 40-V (D-S) MOSFET with Sensing Diode

| PRODUCT SUMMARY | | |
|-------------------|----------------------------|-----------------|
| $V_{(BR)DSS}$ (V) | $r_{DS(on)}$ (Ω) | I_D (A) |
| 40 | 0.0045 at $V_{GS} = 10$ V | 60 ^a |
| | 0.0065 at $V_{GS} = 4.5$ V | 20 ^a |

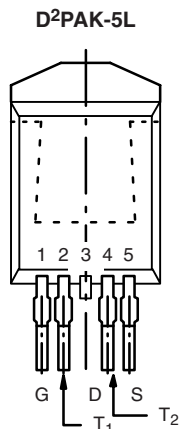
FEATURES

- TrenchFET[®] Power MOSFETS Plus Temperature Sensing Diode
- 175 °C Junction Temperature
- Low Thermal Resistance Package

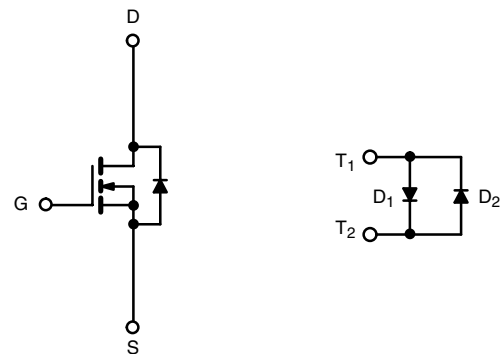

 Available
RoHS*
 COMPLIANT

APPLICATIONS

- Industrial



Ordering Information: SUM60N04-05LT
 SUM60N04-05LT-E3 (Lead (Pb)-free)



N-Channel MOSFET

| ABSOLUTE MAXIMUM RATINGS $T_C = 25$ °C, unless otherwise noted | | | | |
|--|----------------|-----------------|------|--|
| Parameter | Symbol | Limit | Unit | |
| Drain-Source Voltage | V_{DS} | 40 | V | |
| Gate-Source Voltage | V_{GS} | ± 20 | | |
| Continuous Drain Current ($T_J = 175$ °C) ^d | I_D | $T_C = 25$ °C | A | |
| | | $T_C = 100$ °C | | |
| Pulsed Drain Current | I_{DM} | 250 | | |
| Continuous Diode Current (Diode Conduction) ^d | I_S | 60 ^a | | |
| Avalanche Current | I_{AR} | 60 ^a | | |
| Repetitive Avalanche Energy ^b | E_{AR} | 180 | | |
| Maximum Power Dissipation ^a | P_D | $T_C = 25$ °C | W | |
| | | $T_A = 25$ °C | | |
| Operating Junction and Storage Temperature Range | T_J, T_{stg} | - 55 to 175 | °C | |

| THERMAL RESISTANCE RATINGS | | | | |
|----------------------------------|------------|-------|------|--|
| Parameter | Symbol | Limit | Unit | |
| Junction-to-Ambient ^d | R_{thJA} | 40 | °C/W | |
| Junction-to-Case | R_{thJC} | 0.75 | | |

Notes:

- Package limited.
- Duty cycle ≤ 1 %.
- See SOA curve for voltage derating.
- When mounted on 1" square PCB (FR-4 material).

* Pb containing terminations are not RoHS compliant, exemptions may apply.

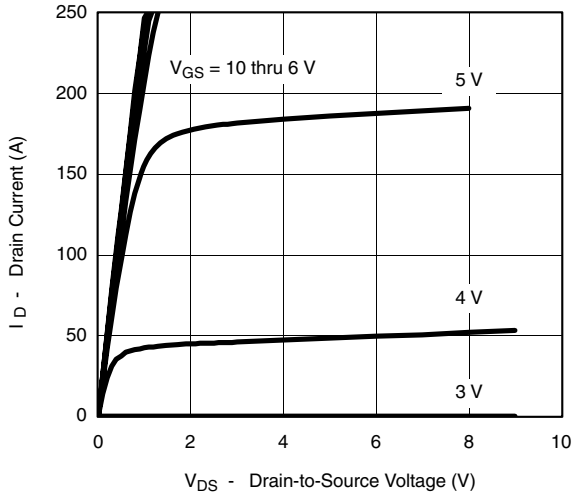
| MOSFET SPECIFICATIONS $T_J = 25\text{ }^\circ\text{C}$, unless otherwise noted | | | | | | |
|--|-------------------------|--|------|--------|-----------|---------------|
| Parameter | Symbol | Test Conditions | Min. | Typ. | Max. | Unit |
| Static | | | | | | |
| Drain-Source Breakdown Voltage | $V_{(BR)DSS}$ | $V_{GS} = 0\text{ V}, I_D = 250\text{ }\mu\text{A}$ | 40 | | | V |
| Gate-Threshold Voltage | $V_{GS(th)}$ | $V_{DS} = V_{GS}, I_{DS} = 250\text{ }\mu\text{A}$ | 1 | | 3 | |
| Gate-Body Leakage | I_{GSS} | $V_{DS} = 0\text{ V}, V_{GS} = \pm 20\text{ V}$ | | | ± 100 | nA |
| Zero Gate Voltage Drain Current | I_{DSS} | $V_{DS} = 40\text{ V}, V_{GS} = 0\text{ V}$ | | | 1 | μA |
| | | $V_{DS} = 40\text{ V}, V_{GS} = 0\text{ V}, T_J = 125\text{ }^\circ\text{C}$ | | | 50 | |
| | | $V_{DS} = 40\text{ V}, V_{GS} = 0\text{ V}, T_J = 175\text{ }^\circ\text{C}$ | | | 500 | |
| On-State Drain Current ^a | $I_{D(on)}$ | $V_{DS} = 5\text{ V}, V_{GS} = 10\text{ V}$ | 120 | | | A |
| Drain-Source On-State Resistance ^a | $r_{DS(on)}$ | $V_{GS} = 10\text{ V}, I_D = 60\text{ A}$ | | 0.0035 | 0.0045 | Ω |
| | | $V_{GS} = 4.5\text{ V}, I_D = 20\text{ A}$ | | 0.0051 | 0.0065 | |
| | | $V_{GS} = 10\text{ V}, I_D = 60\text{ A}, T_J = 125\text{ }^\circ\text{C}$ | | | 0.0069 | |
| | | $V_{GS} = 10\text{ V}, I_D = 60\text{ A}, T_J = 175\text{ }^\circ\text{C}$ | | | 0.0086 | |
| Sense Diode Forward Voltage | V_{FD1} and V_{FD2} | $I_F = 50\text{ }\mu\text{A}$ | 655 | | 715 | mV |
| | | $I_F = 25\text{ }\mu\text{A}$ | 600 | | 660 | |
| Sense Diode Forward Voltage Increase | ΔV_F | From $I_F = 25\text{ }\mu\text{A}$ to $I_F = 50\text{ }\mu\text{A}$ | 30 | | 80 | |
| Forward Transconductance ^a | g_{fs} | $V_{DS} = 15\text{ V}, I_D = 20\text{ A}$ | | 35 | | S |
| Dynamic^b | | | | | | |
| Input Capacitance | C_{iss} | $V_{GS} = 0\text{ V}, V_{DS} = 25\text{ V}, f = 1\text{ MHz}$ | | 6000 | | μF |
| Output Capacitance | C_{oss} | | | 1100 | | |
| Reverse Transfer Capacitance | C_{rss} | | | 700 | | |
| Total Gate Charge ^c | Q_g | $V_{DS} = 20\text{ V}, V_{GS} = 10\text{ V}, I_D = 25\text{ A}$ | | 130 | | nC |
| Gate-Source Charge ^c | Q_{gs} | | | 25 | | |
| Gate-Drain Charge ^c | Q_{gd} | | | 40 | | |
| Turn-On Delay Time ^c | $t_{d(on)}$ | $V_{DD} = 20\text{ V}, R_L = 0.8\text{ }\Omega$ $I_D \cong 25\text{ A}, V_{GEN} = 10\text{ V}, R_g = 2.5\text{ }\Omega$ | | 15 | 20 | ns |
| Rise Time ^c | t_r | | | 80 | 120 | |
| Turn-Off Delay Time ^c | $t_{d(off)}$ | | | 100 | 150 | |
| Fall Time ^c | t_f | | | 100 | 150 | |
| Source-Drain Diode Ratings and Characteristics $T_C = 25\text{ }^\circ\text{C}^b$ | | | | | | |
| Continuous Current | I_S | | | | 60 | A |
| Pulsed Current | I_{SM} | | | | 200 | |
| Forward Voltage ^a | V_{SD} | $I_F = 60\text{ A}, V_{GS} = 0\text{ V}$ | | 1.0 | 1.5 | V |
| Reverse Recovery Time | t_{rr} | $I_F = 60\text{ A}, di/dt = 100\text{ A}/\mu\text{s}$ | | 60 | 90 | ns |
| Peak Reverse Recovery Current | $I_{RM(REC)}$ | | | 2.1 | 4 | A |
| Reverse Recovery Charge | Q_{rr} | | | 0.065 | 0.18 | μC |

Notes:

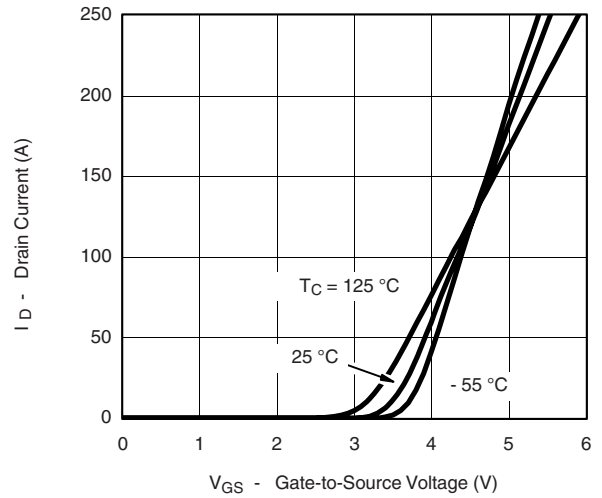
- a. Pulse test; pulse width $\leq 300\text{ }\mu\text{s}$, duty cycle $\leq 2\%$.
- b. Guaranteed by design, not subject to production testing.
- c. Independent of operating temperature.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

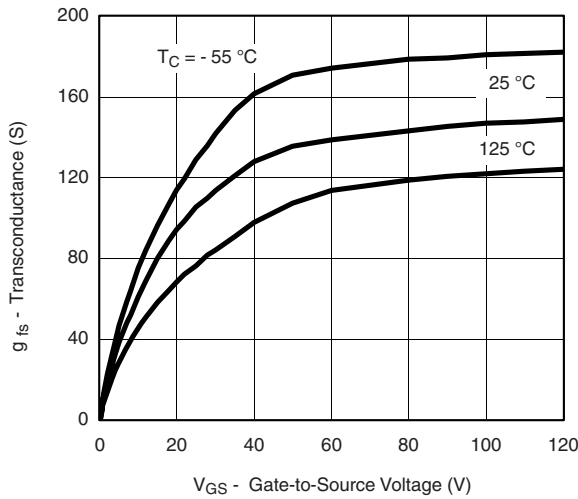
TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



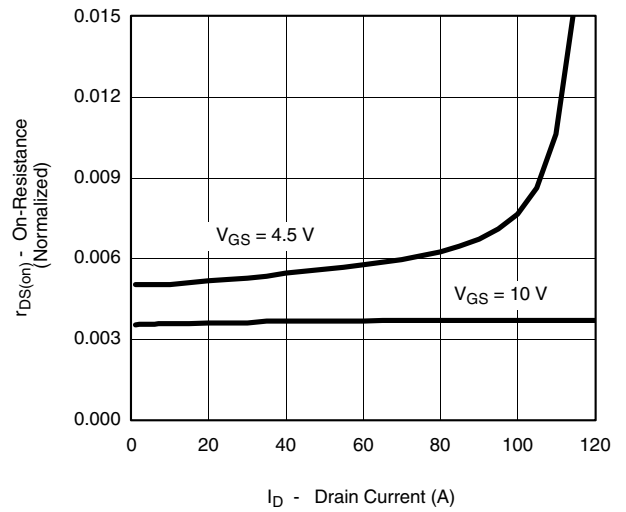
Output Characteristics



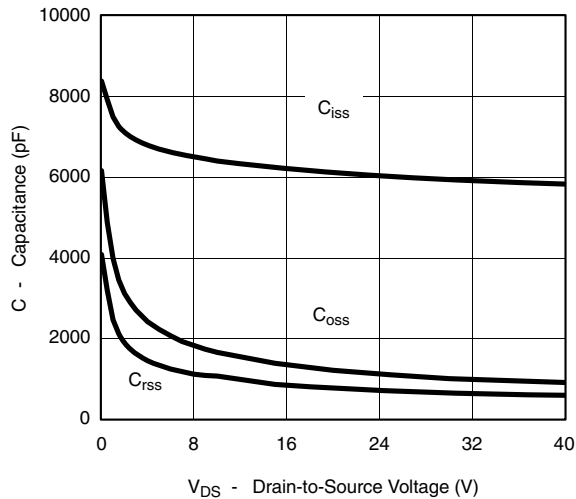
Transfer Characteristics



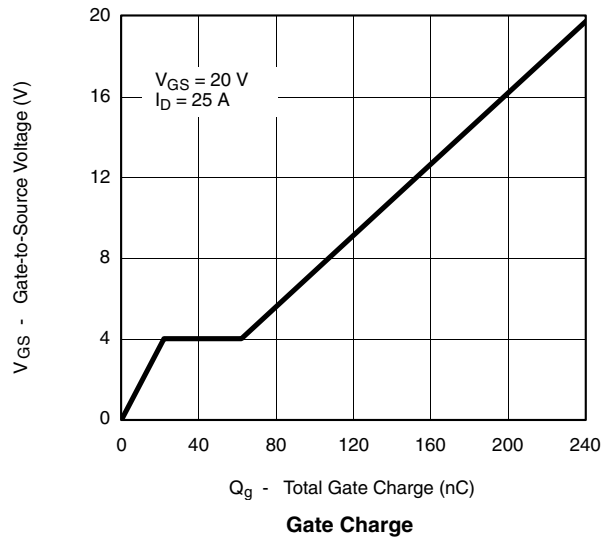
Transconductance



On-Resistance vs. Drain Current

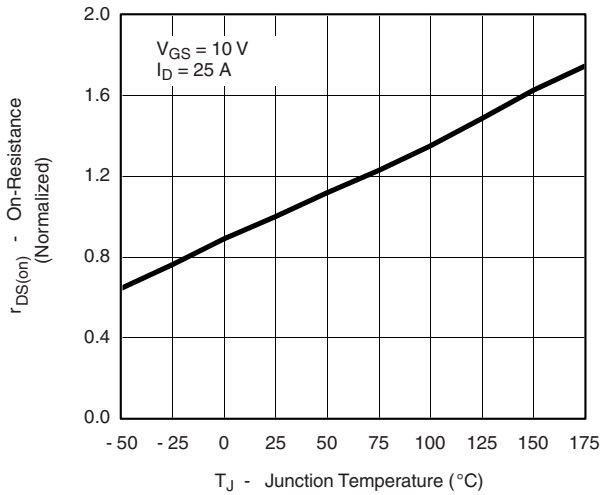


Capacitance

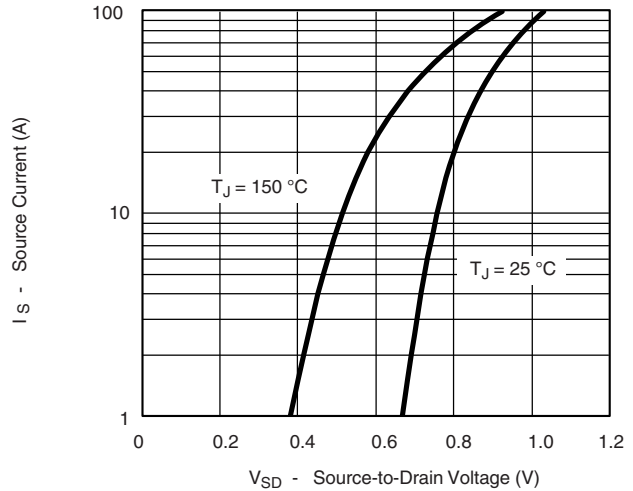


Gate Charge

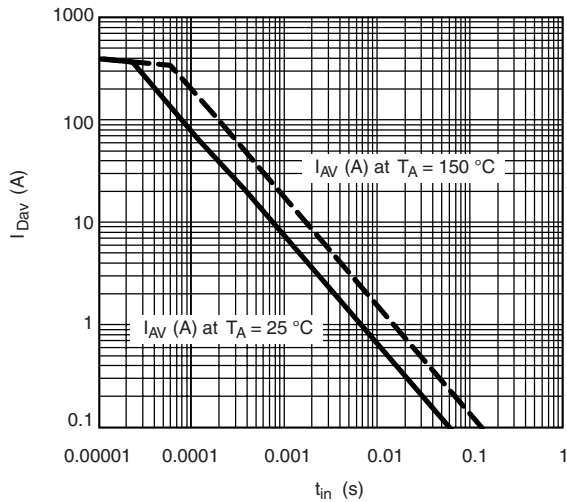
TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



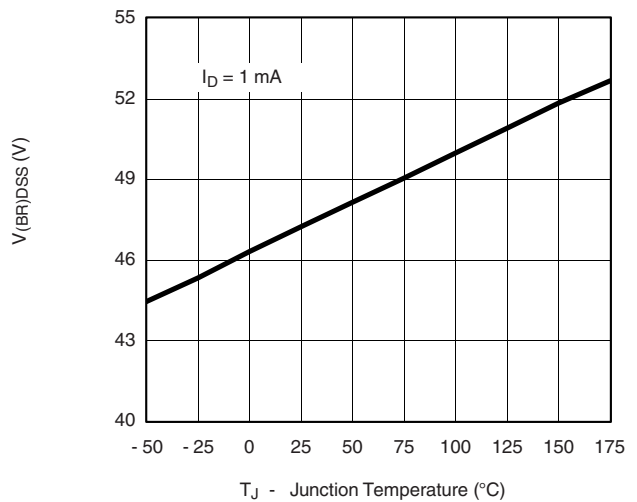
On-Resistance vs. Junction Temperature



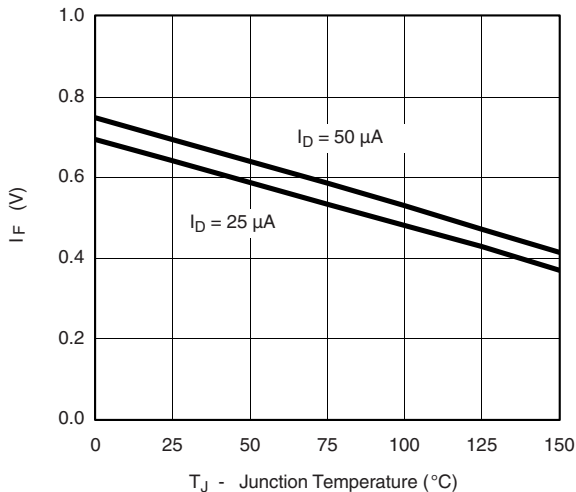
Source-Drain Diode Forward Voltage



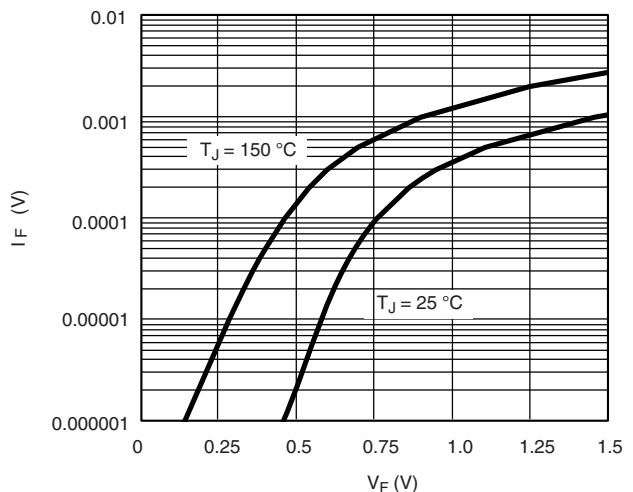
Avalanche Current vs. Time



Drain Source Breakdown vs. Junction Temperature

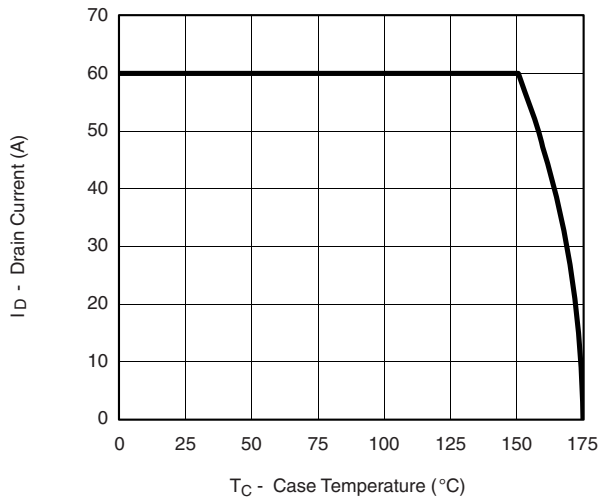


Sense Diode Forward Voltage vs. Temperature

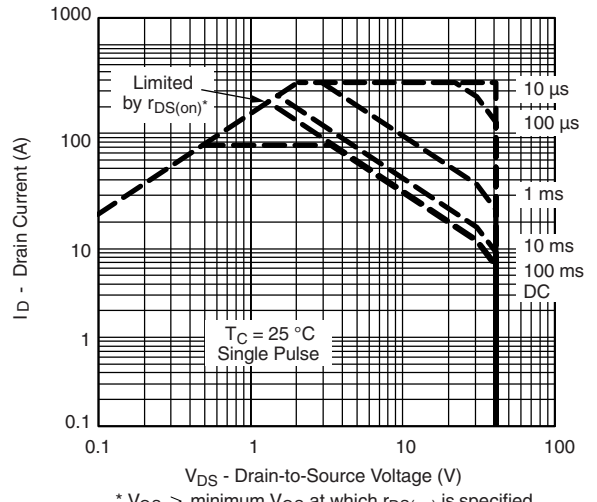


Sense Diode Forward Voltage

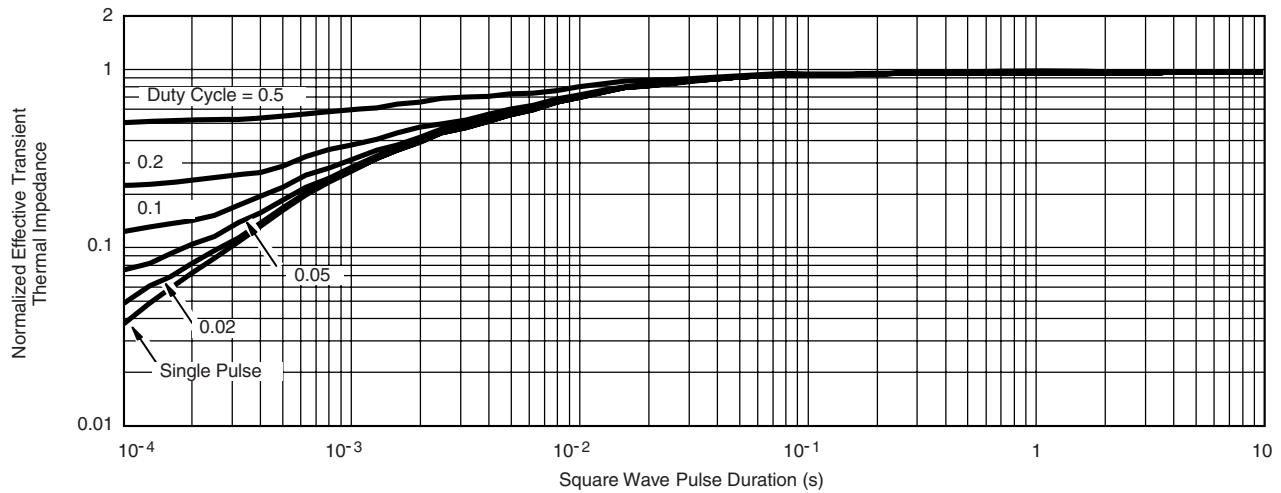
THERMAL RATINGS



Maximum Avalanche and Drain Current vs. Case Temperature



Safe Operating Area



Normalized Thermal Transient Impedance, Junction-to-Case

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